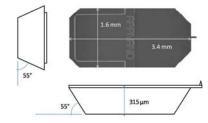
APPNANO probes are compatible with most commercially available SPMs. These probes are nanofabricated using highly doped single crystal silicon with unparalleled reproducibility, robustness and sharpness for consistent high resolution imaging capabilities.

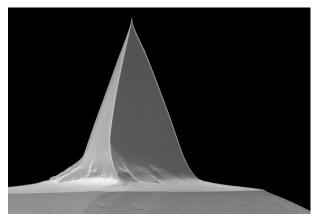
ACLA Probes are designed for non-contact, tapping mode, intermittent contact, and/or close contact applications. The long ACLA cantilever allows larger laser clearance. The reflex side is coated with aluminum for increased laser signal quality.

Handle Chip Specifications		
LxWxT	3.4 mm x 1.6 mm x 315 μm	
Alignment Grooves	YES	

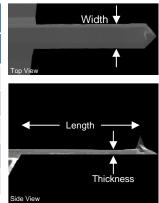


Tip Specifications		
Shape	Pyramidal	
Height (µm)	14 - 16	
ROC (nm)	6	
Coating	None	

Cantilever Specifications			
Material	Si		
Shape	Rectangular		
Reflex Side Coating	Al, $50 \text{ nm} \pm 5 \text{ nm}$		



Parameter -	Value		
	Nominal	Minimum	Maximum
Spring Constant (N/m)	58	36	90
Frequency (kHz)	190	160	225
Length (µm)	225	215	235
Width (µm)	40	35	45
Thickness (µm)	7.8	7.3	8.3



Ordering Information			
Part Number	Probes		
ACLA-10	10		
ACLA-20	20		
ACLA-50	50		
ACLA-200	200		
ACLA-W	410 - 424		

NOTES:

- The specification range is guaranteed. The values of spring constant and frequency are calculated using mathematical formulation
- These probes feature alignment grooves compatible with all alignment chips available in the market.
- Please contact our distributor in your area to order the probes.
- For more technical information, please contact either our distributor in your area or e-mail us directly at info@appnnano.com

Applied NanoStructures, Inc.

E-mail: info@appnano.com

415 Clyde Avenue, Suite 102, Mountain View, CA 94043, USA

Tel: 1 650 988 9880 Fax: 1 408 516 4917



